

Notice of References Cited	Application/Control No. 10/676,707	Applicant(s)/Patent Under Reexamination TOM-MOY ET AL.	
	Examiner Leon Y. Lum	Art Unit 1641	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,132,242	07-1992	Cheung, Sau W.	436/501
	B	US-5,891,630	04-1999	Eggers et al.	435/6
	C	US-6,545,758	04-2003	Sandstrom, Perry	356/317
	D	US-6,660,533	12-2003	Mallet et al.	436/518
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Park et al. Array-based electrical detection of DNA with nanoparticle probes. Science (2002), vol. 295, pp. 1503-1505.
	V	Fluke Corporation. Model 187 & 189 True RMS Multimeter Users Manual, 2002, pp. 2-4, 2-17, 3-6, and 3-7.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.